INVENTORS NAME: Edmun ChianSong Seng et al. DOCKET NO.: 934.138US1

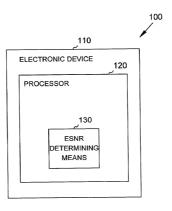


FIG. 1

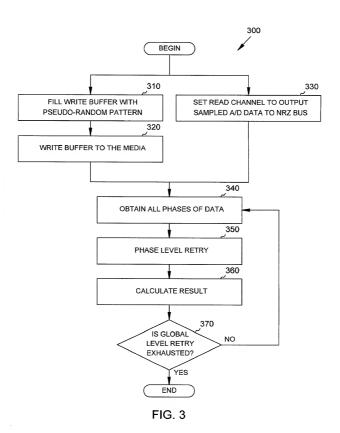
INVENTORS NAME: Edmun ChianSong Seng et al. DOCKET NO.: 934.138US1 2/12 BEGIN 200 210 FILL WRITE BUFFER WITH 127 BITS PSEUDO-RANDOM PATTERN 215 SET READ CHANNEL TO OUTPUT SAMPLED ADC DATA TO NRZ BUS 220 WRITE TO MEDIA FOR 1 DATA WEDGE LENGTH SET PHASE=0 225 READ ALL PHASES 230 245 VERIFY ALL PHASES READ FAILED PHASE NO 235 240 ALL PHASE NO **PHASES** RETRY QUALIFIED? EXHAUSTED? YES YES 250 CALCULATE ESNR 255 260 IS ESNR< NO NO GLOBAL RETRY THRESHOLD? EXHAUSTED? YES 265 YES 270 PASS FAIL

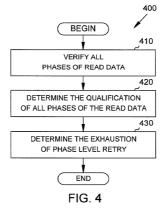
END

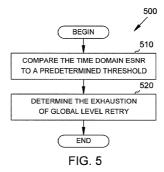
FIG. 2

INVENTORS NAME: Edmun ChianSong Seng et al. DOCKET NO.: 934.138US1

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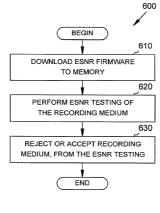


FIG. 6

750 STORAGE MEDIUM PROCESSOR

ESNR DETERMINER

ELECTRONIC DEVICE

700

FIG. 7

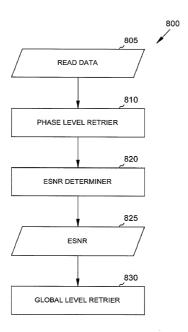


FIG. 8

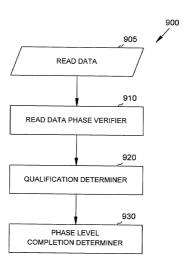


FIG. 9

INVENTORS NAME: Edmun ChianSong Seng et al. DOCKET NO.: 934.138US1

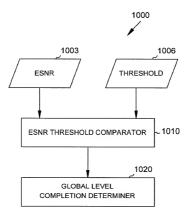


FIG. 10

INVENTORS NAME: Edmun ChianSong Seng et al. DOCKET NO.: 934.138US1

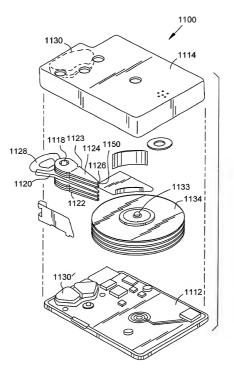


FIG. 11

DOCKET NO.: 934.138US1

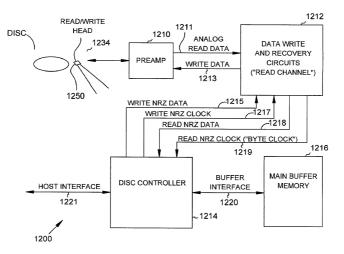


FIG. 12

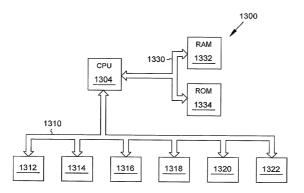


FIG. 13